



Application/Control	No. Applicant(s)/Patent und Reexamination	er
10/619,089	CARDEI ET AL.	
Examiner	Art Unit	
Meless N. Zewdu	2617	

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Class	Subclass	Date	Examiner
455	452.1- 452.2	12/6/2006	M.Z.
455	433-434	12/6/2006	M.Z.
455	445, 464	12/6/2006	M.Z.
455	41.2-41.3	12/6/2006	M.Z.
45	447-451	12/6/2006	M.Z.
455	453-455	12/6/2006	M.Z.
455	502-503	12/6/2006	M.Z.
455	500	12/6/2006	M.Z.
455	507-519	12/6/2006	M.Z.
455	524-528	12/6/2006	M.Z.
455	550.1	12/6/2006	M.Z.
455	556.2	12/6/2006	M.Z.
455	560-561	12/6/2006	M.Z.
455	557-558	12/6/2006	M.Z.

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

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 DATE	EXMR
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Search Notes (continued)



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10/619,089	CARDEI ET AL.	
Examiner	Art Unit	_
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SEARCHED			
Class	Subclass	Date	Examiner
370	395.4- 395.42	12/6/2006	M.Z.
370	395.3	12/6/2006	M.Z.
370	230-235	12/6/2006	M.Z.
370	400-417	12/6/2006	M.Z.
370	420, 473	12/6/2006	M.Z.
370	442-452	12/6/2006	M.Z.
370	310.2	12/6/2006	M.Z.
370	328-334	12/6/2006	M.Z.
370	336-338	12/6/2006	M.Z.
370	317	12/6/2006	M.Z.
370	346-350	12/6/06	M.Z.
455	403, 418	12/6/2006	M.Z.
455	422.1	12/6/2006	M.Z.
455	427-431	12/6/2006	M.Z.

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Searche strategy and techniques: EAST (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT & IBM-TDB).	12/5/2006	M.Z.
Inventor search	12/5/2006	M.Z.
For text serarche terminalogies, please see the attached text search printout.	12/6/2006	M.Z.
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